## Notice of References Cited Application/Control No. 10/576,975 Applicant(s)/Patent Under Reexamination KRUMMEL ET AL. Examiner MICHAEL R. VAUGHAN 2131 Applicant(s)/Patent Under Reexamination KRUMMEL ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0090912 A1	07-2002	Cannon et al.	455/41
*	В	US-2002/0132605 A1	09-2002	Smeets et al.	455/411
*	С	US-2003/0002678 A1	01-2003	Kim, Su-Hwan	380/270
*	D	US-2003/0149875 A1	08-2003	Hosaka, Chisei	713/168
*	Е	US-2004/0043790 A1	03-2004	Ben-David et al.	455/558
*	F	US-2004/0128509 A1	07-2004	Gehrmann, Christian	713/171
*	G	US-2004/0176071 A1	09-2004	Gehrmann et al.	455/411
*	Ι	US-2005/0021940 A1	01-2005	Ma, Kenneth	713/155
*	ı	US-2005/0107046 A1	05-2005	Desbarats et al.	455/090.3
*	7	US-7,127,541 B2	10-2006	Govindarajulu et al.	710/300
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2002290412 A	10-2002	Japan	CANNON et al.	H04L 12/28
	0					
	Р					
	Ø					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	C						
	V						
	w						
	х						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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